

AMENDMENTS TO THE CLAIMS

1. (Currently Amended) A method for inspecting a display device substrate having a plurality of signal wirings and a plurality of electrostatic discharge damage (ESD) protection devices, each of the ESD protection devices being respectively on a corresponding one of the signal wirings, the method comprising steps of:

short-circuiting each of at least one of the ESD protection devices separately to form a current path on each of the corresponding one of the signal wirings;

supplying a current to the corresponding one of the signal wirings; and

determining a defectiveness of the corresponding at least one of the signal wirings depending on the current flowing on the corresponding one of the signal wirings.

2. (Currently Amended) The method according to claim 1, wherein the short-circuiting step comprises short-circuiting the at least one of the ESD protection devices by a conductive shorting bar.

3. (Currently Amended) The method according to claim 1, wherein the step of supplying the current to the corresponding one of the signal wirings includes:

supplying a high voltage through a first shorting wiring connected to the corresponding one of the signal wirings; and

supplying a low voltage through a second shorting wiring connected to the at least one of the ESD protection devices.

4. (Previously Presented) The method according to claim 1, wherein in the short-circuiting step, the display device substrate is a TFT array substrate of a liquid crystal display.

5-10. (Cancelled)

11. (Currently Amended) An apparatus for inspecting a display device substrate having a plurality of signal wirings and a plurality of electrostatic discharge damage (ESD) protection devices, each of the ESD protection devices being respectively on a corresponding one of the signal wirings, the apparatus comprising:

a conductive shorting bar to short-circuit each of at least one of the ESD protection devices separately;

a power supply to supply a current to the corresponding one of the signal wirings; and

a detection circuit to determine a defectiveness of the corresponding at least one of the signal wirings depending on the current flowing on the corresponding one of the signal wirings.

12. (Original) The apparatus according to claim 11, wherein the conductive shorting bar is provided in a jig.

13. (Currently Amended) The apparatus according to claim 11, further comprising:

a first shorting wiring connected to the corresponding one of the signal wirings; and

a second shorting wiring connected to the at least one of the ESD protection devices,

wherein the power supply supplies a high voltage to the corresponding one of the signal

wirings through the first shorting wiring, and a low voltage to the at least one of the ESD protection devices through the second shorting wiring.

14. (Original) The apparatus according to claim 11, wherein the display device substrate is a TFT array substrate of a liquid crystal display.

15-22. (Cancelled)

23. (New) A method for inspecting a display device substrate having a plurality of signal wirings and a plurality of electrostatic discharge damage (ESD) protection devices, the method comprising steps of:

short-circuiting the ESD protection devices to form a current path on each of the signal wirings;

supplying a current to the signal wirings, the step of supplying the current to the signal wirings including:

supplying a high voltage through a first shorting wiring connected to the signal wirings; and

supplying a low voltage through a second shorting wiring connected to the ESD protection devices; and

determining a defectiveness of at least one of the signal wirings depending on the current flowing on the signal wirings.

24. (New) An apparatus for inspecting a display device substrate having a plurality of signal wirings and a plurality of electrostatic discharge damage (ESD) protection devices, the apparatus comprising:

a conductive shorting bar to short-circuit the ESD protection devices;

a power supply to supply a current to the signal wirings;

a detection circuit to determine a defectiveness of at least one of the signal wirings depending on the current flowing on the signal wirings;

a first shorting wiring connected to the signal wirings; and

a second shorting wiring connected to the ESD protection devices,

wherein the power supply supplies a high voltage to the signal wirings through the first shorting wiring, and a low voltage to the ESD protection devices through the second shorting wiring.

25. (New) An apparatus for inspecting a display device substrate having a signal wiring and an electrostatic discharge damage (ESD) protection device connected to the signal wiring, the apparatus comprising:

a conductive shorting bar to short-circuit the ESD protection device;

a power supply to supply a current to the signal wiring; and

a detection circuit to determine a defectiveness of the signal wiring depending on the current flowing on the signal wirings.